## Copper CVD: Applications and Potential Recycle

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#### **PRESENTATION OUTLINE**

- ▲ Applications for copper CVD.
- ▲ Introduction to precursor chemistry.
- ▲ Chemical delivery, processing issues.
- ▲ Abatement versus recycle of CVD effluent.
- ▲ Summary.



## **Applications for copper CVD**

- Provide ultra-thin conformal copper seed layers for electroplated copper.
- ▲ Enable new copper CVD Superfill.
- All 'dry' CVD copper full-fill capability vs. electroplated copper
  - Avoids the use of stand alone e-plating tool.
  - All metal film processing from diffusion barrier to copper seed to full-fill achieved on one tool without vacuum break.



## Copper CVD superfill using CupraSelect

- ▲ Use of catalytic iodine surfactant. E.S. Hwang, J. Lee, <u>Chem. Mater</u>. 2000, 12, 2076- 2081.
- ▲ Copper fills from the bottom of the feature first.





#### **CUPRA SELECT**®

- ▲ Stable yellow liquid Cu(hfac)(tmvs), premier copper precursor.
- ▲ Vapor pressure 1 Torr @ 60°C.
- ▲ Provides 99.99% copper , 1.85 µohm cm<sup>1</sup>, 5000 A/min.
- ▲ Conformality > 90%

<sup>1</sup>J. Norman et al Thin Solid Films 262 (1995) 46-51





#### **CVD COPPER FILM GROWTH**

Metallization by disproportionation





#### **METALLIZATION CHEMISTRY**

- Selective deposition onto conductors due to key electron transfer step.
- Superior metallization process by the use of additives.
  - tmvs for stable precursor delivery.
  - hfac and water (separately or as HDH) for enhanced metallization.
  - water addition alone promotes adhesion.



#### **EVOLUTION OF CUPRA SELECT PROCESSING WITH ADDITIVES**

▲ Enhanced thermal stability during DLI evaporation. Cu<sup>1</sup>(hfac)(tmvs) + tmvs → Cu<sup>°</sup> T. Omstead (Sandia)

▲ Enhanced deposition rate for copper.
Cu<sup>1</sup>(hfac)(tmvs) + H<sub>2</sub>O → Cu<sup>°</sup>
A. V. Gelatos et al Appl Phys Lett., 63 (20) (1993) 2842.

#### ▲ Enhanced deposition rate, uniformity and reflectivity. Cu<sup>1</sup>(hfac)(tmvs) + Hhfac → Cu<sup>°</sup> J. Norman et al Conference proceedings ULSI-IX 1994 MRS



#### COMBINING THE ACCELERANT ADDITIVES Hhfac AND WATER INTO ONE COMPOUND: Hhfac DIHYDRATE

- Release of Hhfac and H<sub>2</sub>O occur under CVD conditions, assuming adequate residence times for dissociation in the CVD chamber.
- Cu(hfac)(tmvs)/hydrate blend can be stabilized by tmvs addition.
- ▲ Improved adhesion of copper to some TiN, but additional water needed for Ta and TaN.







#### SUMMARY OF ADDITIVE TRENDS

	Adhesion	Uniformity	Dep. Rate	Resistance	Reflectivity	DLI Performance
tmvs	0	0	(-)1	(-)2	(-) <sup>3</sup>	+
Hhfac	0	+	+	0	+	(-)
$H_2O$	+	(+)	+	(-)4		(-)
HDH	(+) <sup>5</sup>	+	+	0	+	(-)

#### Legend:

- + = improves
- = degrades
- 0 = no effect
- () = lesser effect
- 1) Disproporation suppressed.
- 2) Resistance can appear higher due to film roughness.
- 3) Degraded by higher roughness.
- 4) Excess water yield copper oxides.
- 5) Improves adhesion on some TiN.





## Hydrogen as a reducing agent:

2 Cu(hfac)(tmvs)+ H<sub>2</sub>= Cu° + 2 Hhfac + 2tmvs Arita et al J. Electrochem. Soc., Vol 142, No9, 3173 (1995)

Compare to disproportionation:
2 Cu(hfac)(tmvs) = Cu° + Cu<sup>+2</sup>(hfac)<sub>2</sub> + 2 tmvs





## WAFER METALLIZATION SCENARIO

- ▲ At 2000A/min, 0.25m 6:1 AR
- ▲ On an 8 inch wafer 0.5 microns copper film corresponds to 0.144g copper metal.
- ▲ Assume 30% utilization efficiency of copper precursor entering the reactor.
- 2.5g of CupraSelect will be consumed during the process step, but approx 70% of this remains unchanged as it exits the process chamber as effluent.

### ABATEMENT SCENARIOS FOR REACTOR EFFLUENT

▲ Destructive capture of CVD effluent.

- pyrolysis in a hot-box.
- chemical absorption by a caustic scrubber.
- ultimate disposal of copper waste.
- ▲ Reversible physical entrapment for recycle
  - no copper waste for disposal, environmentally benign.
  - complete recycle for copper containing CVD byproducts.
  - lowered COO to end user.



#### **Destructive abatement**

- Precursor vapor contacted with alkaline metal oxides at high temperature to fragment fluorocarbon ligands to give metal fluorides, HF,CHF<sub>x</sub> etc.
- Any residual flammable vapors are combusted in burn box to give carbon dioxide, water and HF
- ▲ HF vapors and carbon dioxide need alkaline scrubber for absorbtion
- Copper deposited as waste metal or metal fluoride for disposal.
- ▲ High value-added molecules irreversibly consumed.



# Collection of copper metal and $Cu^{+2}(hfac)_2$

▲ Applied Materials US 6099649







#### **Regeneration of Hhfac ligand**

▲ Air Products US 6046364





#### **Production of CupraSelect**

▲ Regenerated Hhfac recycled back to give fresh precursor. Air Products US 6096913.



**ISO 9001 Certified** 



#### **SUMMARY**

- CupraSelect is attractive for commercial implementation of copper CVD for e-plate seed, CVD superfill, all 'dry' full-fill CVD.
  - Adaptable precursor properties
  - Simple thermal CVD process.
  - Excellent film properties.
  - Potential for minimal environmental impact via fluorinated ligand and copper recycle.

